

## Issues in Empirical Machine Learning Research

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## Issues in ML Research

- A brief introduction
- (Ever) progressing insights from past 10 years:
  - The curse of interaction
  - Evaluation metrics
  - Bias and variance
  - There's no data like more data

## Machine learning

- Subfield of artificial intelligence
  - Identified by Alan Turing in seminal 1950 article *Computing Machinery and Intelligence*
- (Langley, 1995; Mitchell, 1997)
- Algorithms that learn from examples
  - Given task T, and an example base E of examples of T (input-output mappings: supervised learning)
  - Learning algorithm L is better in task T after learning

## Machine learning: Roots

- Parent fields:
  - Information theory
  - Artificial intelligence
  - Pattern recognition
  - Scientific discovery
- Took off during 70s
- Major algorithmic improvements during 80s
- Forking: neural networks, data mining

## Machine Learning: 2 strands

- **Theoretical ML** (what can be proven to be learnable by what?)
  - Gold, *identification in the limit*
  - Valiant, *probably approximately correct learning*
- **Empirical ML** (on real or artificial data)
  - Evaluation Criteria:
    - Accuracy
    - Quality of solutions
    - Time complexity
    - Space complexity
    - Noise resistance

## Empirical machine learning

- **Supervised learning:**
  - Decision trees, rule induction, version spaces
  - Instance-based, memory-based learning
  - Hyperplane separators, kernel methods, neural networks
  - Stochastic methods, Bayesian methods
- **Unsupervised learning:**
  - Clustering, neural networks
- **Reinforcement learning, regression, statistical analysis, data mining, knowledge discovery, ...**

## Empirical ML: 2 Flavours

- **Greedy**
  - Learning
    - abstract model from data
  - Classification
    - apply abstracted model to new data
- **Lazy**
  - Learning
    - store data in memory
  - Classification
    - compare new data to data in memory

## Greedy vs Lazy Learning

- Greedy:**
  - Decision tree induction
    - CART, C4.5
  - Rule induction
    - CN2, Ripper
  - Hyperplane discriminators
    - Winnow, perceptron, backprop, SVM / Kernel methods
  - Probabilistic
    - Naive Bayes, maximum entropy, HMM, MEMM, CRF
  - (Hand-made rulesets)
- Lazy:**
  - *k*-Nearest Neighbour
    - MBL, AM
    - Local regression

## Empirical methods

- **Generalization performance:**
  - How well does the classifier do on UNSEEN examples?
  - (test data: i.i.d - independent and identically distributed)
  - Testing on training data is not *generalization*, but *reproduction* ability
- **How to measure?**
  - Measure on separate test examples drawn from the same population of examples as the training examples
  - But, avoid single luck; the measurement is supposed to be a trustworthy estimate of the real performance on *any* unseen material.

## *n*-fold cross-validation

- (Weiss and Kulikowski, *Computer systems that learn*, 1991)
- Split example set in *n* equal-sized partitions
- For each partition,
  - Create a training set of the other *n-1* partitions, and train a classifier on it
  - Use the current partition as test set, and test the trained classifier on it
  - Measure generalization performance
- Compute average and standard deviation on the *n* performance measurements

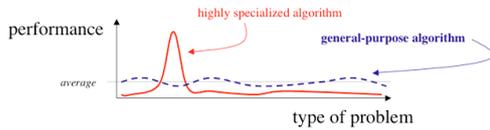
## Significance tests

- Two-tailed paired *t*-tests work for comparing 2 10-fold CV outcomes
  - But many type-I errors (false hits)
- Or 2 × 5-fold CV (Salzberg, *On Comparing Classifiers: Pitfalls to Avoid and a Recommended Approach*, 1997)
- Other tests: McNemar, Wilcoxon sign test
- Other statistical analyses: ANOVA, regression trees
- Community determines what is *en vogue*

## No free lunch

- (Wolpert, Schaffer; Wolpert & Macready, 1997)
  - No single method is going to be best in all tasks
  - No algorithm is always better than another one
  - No point in declaring victory
- **But:**
  - Some methods are more suited for some types of problems
  - No rules of thumb, however
  - Extremely hard to meta-learn too

## No free lunch



(From Wikipedia)

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## Algorithmic parameters

- **Machine learning meta problem:**
  - Algorithmic parameters change bias
    - Description length and noise bias
    - Eagerness bias
  - Can make quite a difference (Daelemans, Hoste, De Meulder, & Naudts, ECML 2003)
  - Different parameter settings = functionally different system
  - But good settings not predictable

## Daelemans et al. (2003): Diminutive inflection

	Ripper	TiMBL
Default	96.3	96.0
Feature selection	96.7	97.2
Parameter optimization	97.3	97.8
Joint	97.6	97.9

## WSD (line)

Similar: little, make, then, time, ...

	Ripper	TiMBL
Default	21.8	20.2
Optimized parameters	22.6	27.3
Optimized features	20.2	34.4
Optimized parameters + FS	33.9	38.6

## Known solution

- **Classifier wrapping (Kohavi, 1997)**
  - Training set → train & validate sets
  - Test different setting combinations
  - Pick best-performing
- **Danger of overfitting**
  - When improving on training data, while *not* improving on test data
- **Costly**

## Optimizing wrapping

- Worst case: exhaustive testing of “all” combinations of parameter settings (pseudo-exhaustive)
- Simple optimization:
  - Not test all settings

## Optimized wrapping

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- Optimizations:
  - ~~Not test all settings~~
  - Test all settings in less time

## Optimized wrapping

- Worst case: exhaustive testing of “all” combinations of parameter settings (pseudo-exhaustive)
- Optimizations:
  - ~~Not test all settings~~
  - Test all settings in less time
  - With less data

## Progressive sampling

- Provost, Jensen, & Oates (1999)
- Setting:
  - 1 algorithm (parameters already set)
  - Growing samples of data set
- Find point in learning curve at which no additional learning is needed

## Wrapped progressive sampling

- (Van den Bosch, 2004)
- Use **increasing** amounts of data
- While validating **decreasing** numbers of setting combinations
- E.g.,
  - Test “all” settings combinations on a small but sufficient subset
  - Increase amount of data stepwise
  - At each step, discard lower-performing setting combinations

## Procedure (I)

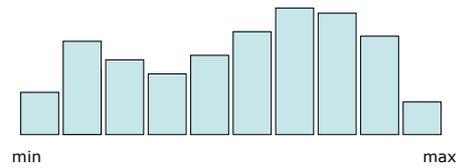
- Given training set of labeled examples,
  - Split internally in 80% training and 20% held-out set
  - Create clipped parabolic sequence of sample sizes
    - $n$  steps  $\rightarrow$  multipl. factor  $n^{\text{th}}$  root of 80% set size
    - Fixed start at 500 train / 100 test
    - E.g. {500, 698, 1343, 2584, 4973, 9572, 18423, 35459, 68247, 131353, 252812, 486582}
    - Test sample is always 20% of train sample

### Procedure (2)

- Create pseudo-exhaustive pool of all parameter setting combinations
- Loop:
  - Apply current pool to current train/test sample pair
  - Separate good from bad part of pool
  - Current pool := good part of pool
  - Increase step
- Until one best setting combination left, or all steps performed (random pick)

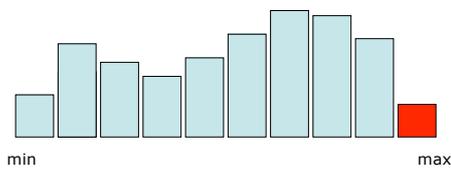
### Procedure (3)

- Separate the good from the bad:



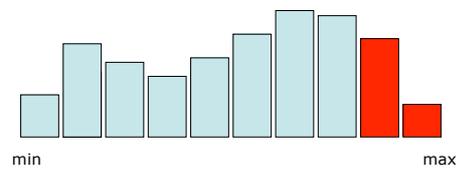
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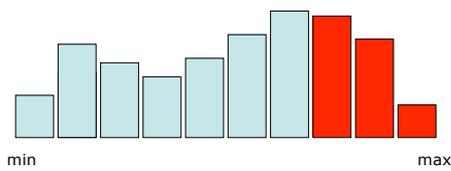
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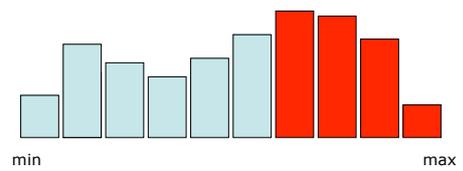
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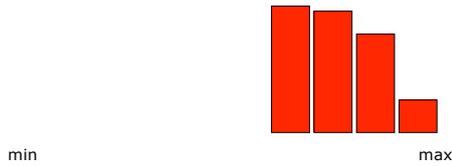
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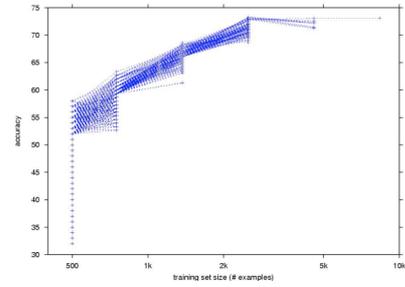


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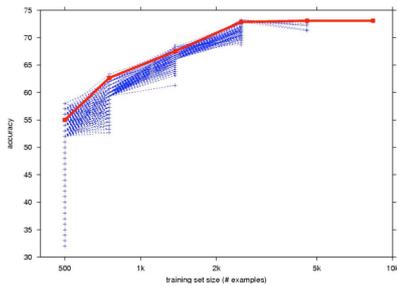
- Separate the good from the bad:



### “Mountaineering competition”



### “Mountaineering competition”



### Customizations

algorithm	# parameters	Total # setting combinations
<b>Ripper</b> (Cohen, 1995)	6	648
<b>C4.5</b> (Quinlan, 1993)	3	360
<b>Maxent</b> (Giuasu et al, 1985)	2	11
<b>Winnow</b> (Littlestone, 1988)	5	1200
<b>IB1</b> (Aha et al, 1991)	5	925

### Experiments: datasets

Task	# Examples	# Features	# Classes	Class entropy
audiology	228	69	24	3.41
bridges	110	7	8	2.50
soybean	685	35	19	3.84
tic-tac-toe	960	9	2	0.93
votes	437	16	2	0.96
car	1730	6	4	1.21
connect-4	67559	42	3	1.22
kr-vs-kp	3197	36	2	1.00
splice	3192	60	3	1.48
nursery	12961	8	5	1.72

### Experiments: results

Algorithm	normal wrapping		WPS	
	Error reduction	Reduction/combination	Error reduction	Reduction/combination
Ripper	16.4	0.025	27.9	0.043
C4.5	7.4	0.021	7.7	0.021
Maxent	5.9	0.536	0.4	0.036
IB1	30.8	0.033	31.2	0.034
Winnow	17.4	0.015	32.2	0.027

## Discussion

- Normal wrapping and WPS improve generalization accuracy
  - A bit with a few parameters (Maxent, C4.5)
  - More with more parameters (Ripper, IBI, Winnow)
  - 13 significant wins out of 25;
  - 2 significant losses out of 25
- Surprisingly close ([0.015 - 0.043]) average error reductions per setting

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  - **Evaluation metrics**
  - Bias and variance
  - There's no data like more data

## Evaluation metrics

- Estimations of generalization performance (on unseen material)
- Dimensions:
  - Accuracy or more task-specific metric
    - Skewed class distribution
    - Two classes vs multi-class
  - Single or multiple scores
    - n-fold CV, leave\_one\_out
    - Random splits
    - Single splits
  - Significance tests

## Accuracy is bad

- Higher accuracy / lower error rate does not necessarily imply better performance on target task
- “The use of error rate often suggests insufficiently careful thought about the real objectives of the research” - David Hand, *Construction and Assessment of Classification Rules* (1997)

## Other candidates?

- Per-class statistics using true and false positives and negatives
  - Precision, recall, F-score
  - ROC, AUC
- Task-specific evaluations
- Cost, speed, memory use, accuracy within time frame

## True and false positives

		True class	
		p	n
Hypothesized class	Y	True Positives	False Positives
	N	False Negatives	True Negatives

Column totals: P N

$$\text{fp rate} = \frac{FP}{N} \quad \text{tp rate} = \frac{TP}{P}$$

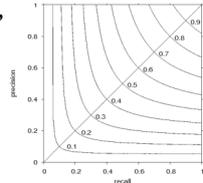
$$\text{precision} = \frac{TP}{TP+FP} \quad \text{recall} = \frac{TP}{P}$$

$$\text{accuracy} = \frac{TP+TN}{P+N} \quad \text{F-measure} = \frac{2}{1/\text{precision}+1/\text{recall}}$$

### F-score is better

- When your problem is expressible as a per-class precision and recall problem
- (like in IR, Van Rijsbergen, 1979)

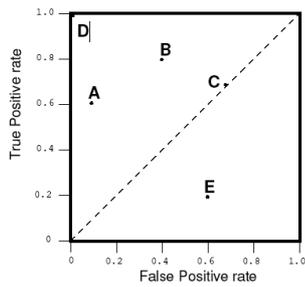
$$F_{\beta=1} = \frac{2pr}{p+r}$$



### ROC is the best

- Receiver Operating Characteristics
- E.g.
  - ECAI 2004 workshop on ROC
  - Fawcett's (2004) ROC 101
- Like precision/recall/F-score, suited "for domains with skewed class distribution and unequal classification error costs."

### ROC curve



### True and false positives

		True class	
		p	n
Hypothesized class	Y	True Positives	False Positives
	N	False Negatives	True Negatives

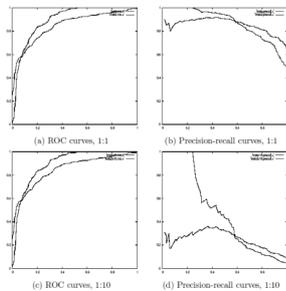
Column totals: P N

fp rate =  $\frac{FP}{N}$       tp rate =  $\frac{TP}{P}$

precision =  $\frac{TP}{TP+FP}$       recall =  $\frac{TP}{P}$

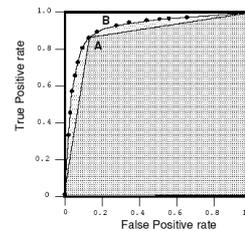
accuracy =  $\frac{TP+TN}{P+N}$       F-measure =  $\frac{2}{1/precision+1/recall}$

### ROC is better than p/r/F



### AUC, ROC's F-score

- Area Under the Curve



## Multiple class AUC?

- AUC per class,  $n$  classes:
- Macro-average:  $\text{sum}(\text{AUC}(c_1) + \dots + \text{AUC}(c_n))/n$
- Micro-average:

$$\text{AUC}_{total} = \sum_{c_i \in C} \text{AUC}(c_i) \cdot p(c_i)$$

## F-score vs AUC

- Which one is better actually depends on the task.
- Examples by Reynaert (2005), spell checker performance on fictitious text with 100 errors:

System	Flagged	Corrected	Recall	Precision	F-score	AUC
A	10,000	100	1	0.01	0.02	0.750
B	100	50	0.5	0.5	0.5	0.747

## Significance & F-score

- $t$ -tests are valid on accuracy and recall
- But are invalid on precision and F-score
- Accuracy is bad; recall is only half the story
- Now what?

## Randomization tests

- (Noreen, 1989; Yeh, 2000; Tjong Kim Sang, CoNLL shared task; *stratified shuffling*)
- Given classifier's output on a *single* test set,
  - Produce many small subsets
  - Compute standard deviation
- Given two classifiers' output,
  - Do as above
  - Compute significance (Noreen, 1989)

## So?

- Does Noreen's method work with AUC? We tend to think so
- Incorporate AUC in evaluation scripts
- Favor Noreen's method in
  - "shared task" situations (single test sets)
  - F-score / AUC estimations (skewed classes)
- Maintain matched paired  $t$ -tests where accuracy is still OK.

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  - **Bias and variance**
  - There's no data like more data

## Bias and variance

Two meanings!

1. **Machine learning bias and variance** - the degree to which an ML algorithm is flexible in adapting to data
2. **Statistical bias and variance** - the balance between systematic and variable errors

## Machine learning bias & variance

- **Naïve Bayes:**
  - High bias (strong assumption: feature independence)
  - Low variance
- **Decision trees & rule learners:**
  - Low bias (adapt themselves to data)
  - High variance (changes in training data can cause radical differences in model)

## Statistical bias & variance

- **Decomposition of a classifier's error:**
  - Intrinsic error: intrinsic to the data. Any classifier would make these errors (*Bayes error*)
  - Bias error: recurring error, systematic error, independent of training data.
  - Variance error: non-systematic error; variance in error, averaged over training sets.
- E.g. Kohavi and Wolpert (1996), *Bias Plus Variance Decomposition for Zero-One Loss Functions*, Proc. of ICML
  - Keep test set constant, and vary training set many times

## Variance and overfitting

- Being too faithful in reproducing the classification in the training data
  - Does not help generalization performance on unseen data - **overfitting**
  - Causes high **variance**
- **Feature selection (discarding unimportant features) helps avoiding overfitting, thus lowers variance**
- Other "smoothing bias" methods:
  - Fewer nodes in decision trees
  - Fewer units in hidden layers in MLP

## Relation between the two?

- **Surprisingly, NO!**
  - A high machine learning bias does not lead to a low number or portion of bias errors.
  - A high bias is not necessarily good; a high variance is not necessarily bad.
  - In the literature: bias error often surprisingly equal for algorithms with very different machine learning bias

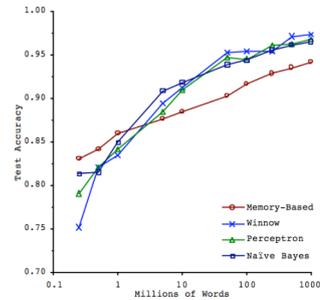
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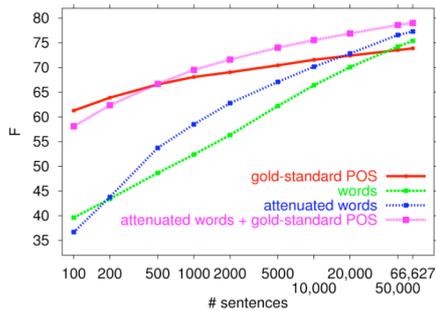
## There's no data like more data

- Learning curves
  - At different amounts of training data,
  - algorithms attain different scores on test data
  - (recall Provost, Jensen, Oats 1999)
- Where is the ceiling?
- When not at the ceiling, do differences between algorithms matter?

## Banko & Brill (2001)



## Van den Bosch & Buchholz (2002)



## Learning curves

- Tell more about
  - the task
  - features, representations
  - how much more data needs to be gathered
  - scaling abilities of learning algorithms
- Relativity of differences found at point when learning curve has not flattened

## Closing comments

- Standards and norms in experimental & evaluative methodology in empirical research fields always on the move
- *Machine learning* and *search* are sides of the same coin
- Scaling abilities of ML algorithms is an underestimated dimension

## Software available at <http://ilk.uvt.nl>

- paramsearch 1.0 (WPS)
- TiMBL 5.1

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## Credits

- **Curse of interaction:** Véronique Hoste and Walter Daelemans (University of Antwerp)
- **Evaluation metrics:** Erik Tjong Kim Sang (University of Amsterdam), Martin Reynaert (Tilburg University)
- **Bias and variance:** Iris Hendrickx (University of Antwerp), Maarten van Someren (University of Amsterdam)
- **There's no data like more data:** Sabine Buchholz (Toshiba Research)